

[54] ELECTRONIC THERMOMETER PROBE

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[**] Term: 14 Years

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[52] U.S. Cl. D10/60
[58] Field of Search D10/57, 60; 374/100, 374/106, 132, 151, 158, 159, 164, 170, 179, 185, 194, 208, 209; 128/236, 207.14

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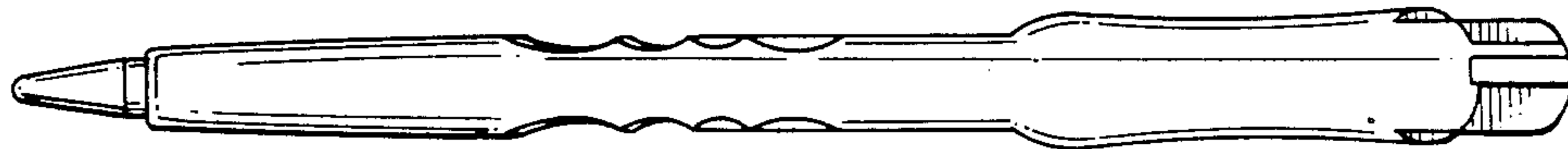
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[57] CLAIM

The ornamental design for a electronic thermometer probe, as shown.

DESCRIPTION

FIG. 1 is a front elevational view of a electronic thermometer probe showing our new design; FIG. 2 is a left side elevational view; FIG. 3 is a right side elevational view; FIG. 4 is a rear elevational view; FIG. 5 is a top plan view; FIG. 6 is a bottom plan view; and FIG. 7 is a cross-sectional view taken along line 7—7 of FIG. 1 thereof.



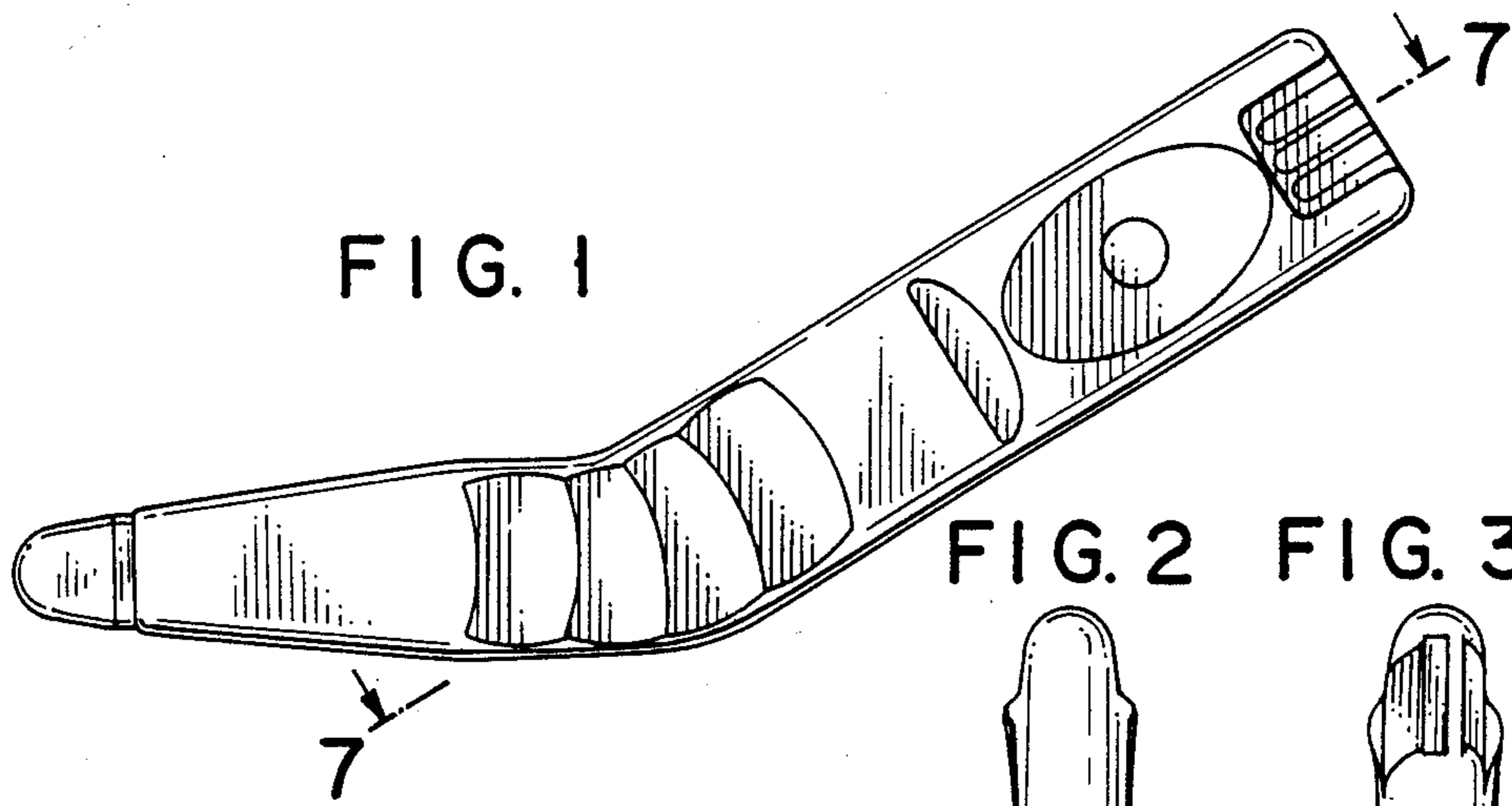


FIG. 2 FIG. 3

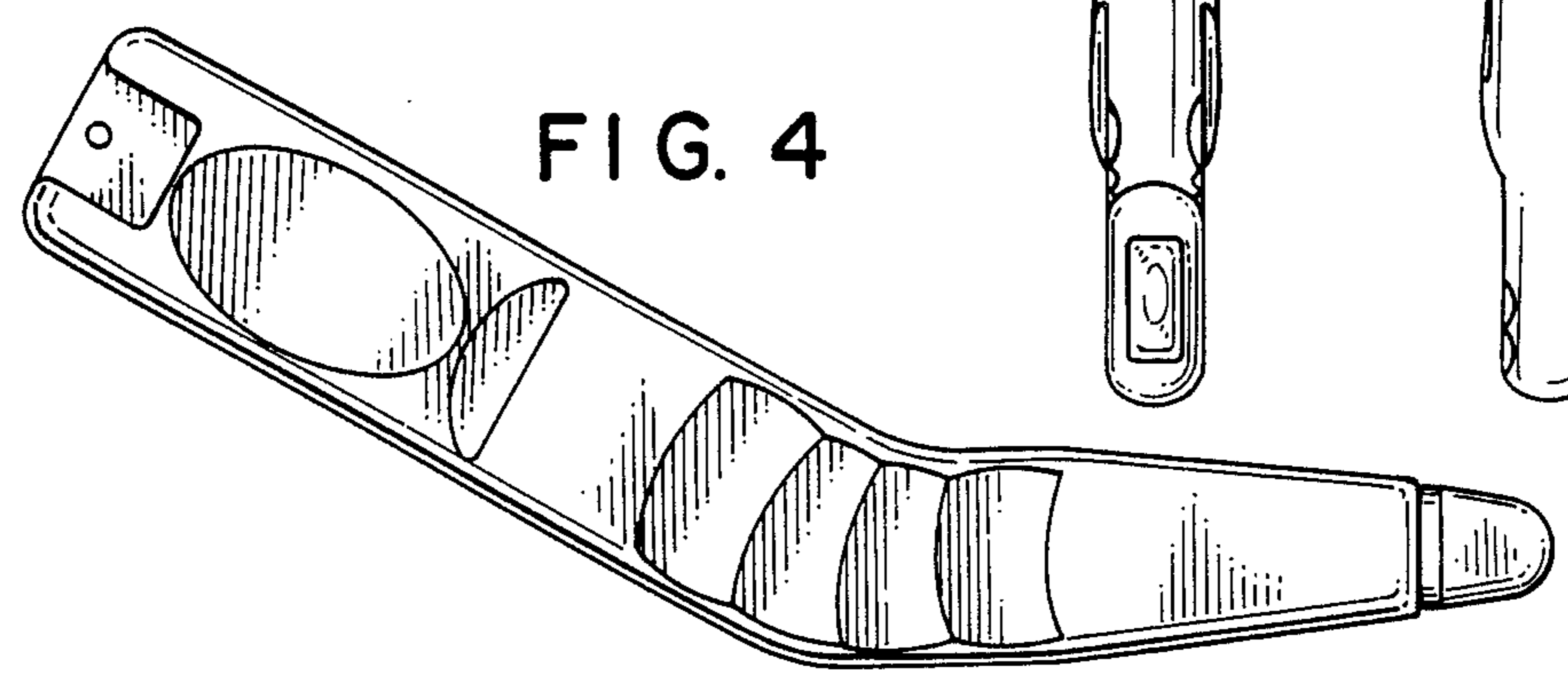
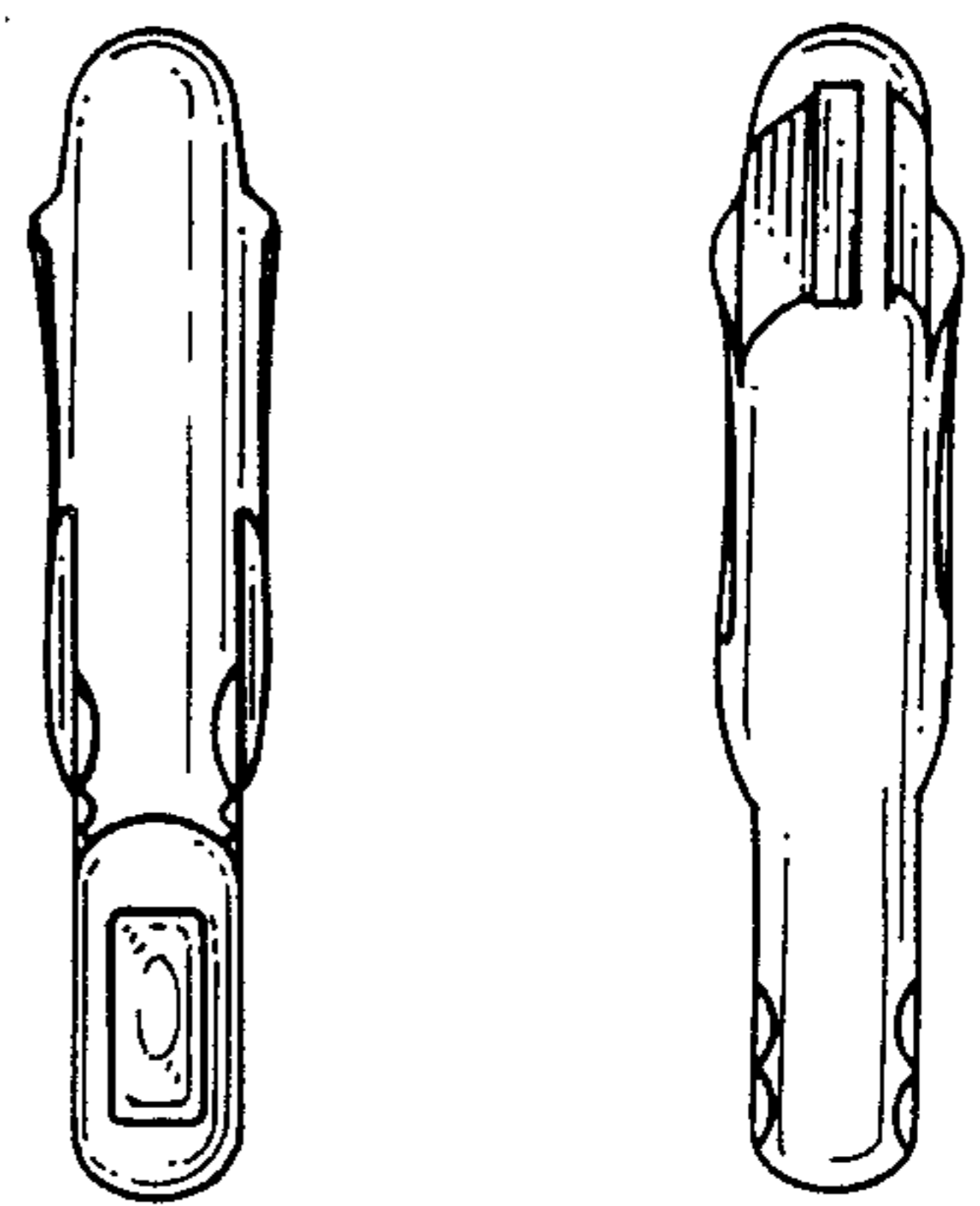


FIG. 5

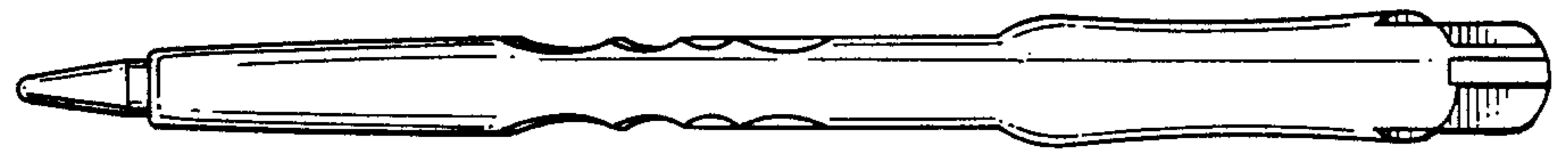


FIG. 6

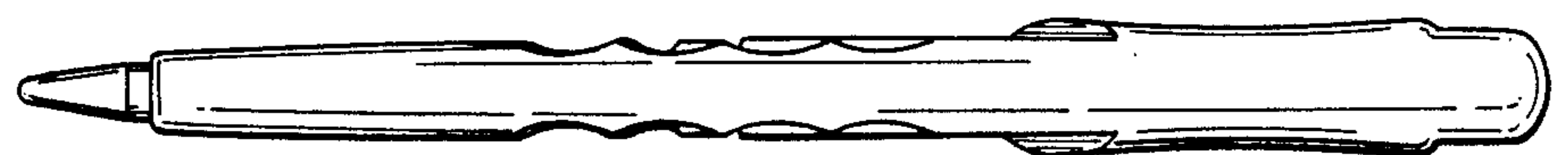


FIG. 7

